



<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10658380</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LEE ET AL.</p>
	<p>Examiner</p> <p>Schindler, David</p>	<p>Art Unit</p> <p>2862</p>


Class	SubClass	Date	Examiner
324	253	6/1/2006	DS

U.S. Patent and Trademark Office	Part of Paper No.: 20060602
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<b><i>Interference Searched</i></b>  	Application/Control No.  10658380	Applicant(s)/Patent Under Reexamination  LEE ET AL.
	Examiner Schindler, David	Art Unit 2862

Class	SubClass	Date	Examiner
324	253	6/1/2006	DS

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<b>Search Notes</b>  	Application/Control No.  10658380	Applicant(s)/Patent Under Reexamination  LEE ET AL.
	Examiner Schindler, David	Art Unit 2862

Notes	Date	Examiner
324/244,249,253,254,255,258,260.ccls. 327/110,172,176.ccls. 33/355R,356,352.ccls. 73/1.76.ccls. (text search - see search history printouts)	5/31/2006	DS
East - text search - see search history printouts	5/31/2006	DS
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